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Spatial Light Modulators LCOS-SLM

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Applications and Features (Laser processing / marking, etc.)

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Related thesis / Technical materials

LCOS-SLM embedded module

Related product:

Structure / Specifications

The LCOS-SLM X15213 series is a reflective liquid crystal device that can control the wavefront of light with high efficiency and high precision by phase modulation.

It consists of a head and a controller connected by a flexible cable.

Structure

Head

Type no.	Number of pixels	Pixel pitch (μm)	Effective area size (mm)	Fill factor (%)	Weight (g)
X15213 series	1272 × 1024	12.5	15.9 × 12.8	96	150 (Water cooled type: 550)

Controller

Type no.	Supply	Power	We	ight			Input	DVI	Power
	voltage AC	supply frequency	Main unit	Including cable	Input signal	DVI signal format	signal level		consumption
	(V)	(Hz)	(g)	(g)		(pixels)	(levels)	(Hz)	(W)
X15213 series	100 to 230	50/60	910	1350	DVI-D/ USB-B (2.0 High-speed)	1280 × 1024	256	60	15

X15213 series

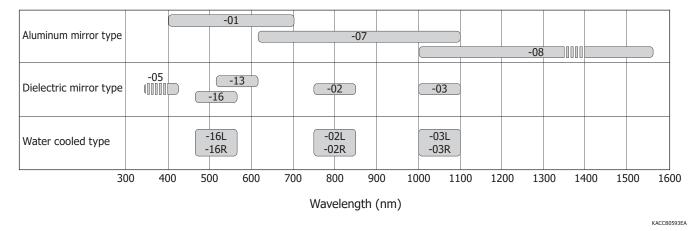


Head

Selection guide

There are eight types in the X15213 series, which cover different wavelengths of light sources. They can be grouped into dielectric mirror types (-02/-03/-05/-13/-16) and aluminum mirror types (-01/-07/-08). To enhance the reflectivity of the device, dielectric mirror types have dielectric mirrors corresponding to different wavelengths of laser light source. [-02: titanium sapphire laser (800 nm band), -03: YAG laser (1064 nm), -05: LD (405 nm), -13: YAG laser 2nd harmonic (532 nm)/He-Ne laser (633 nm), -16: YAG laser 2nd harmonic (532 nm)]. The increased reflectivity achieved by the dielectric mirror decreases the internal absorption rate. This allows accommodation for high powered lasers, but the covered wavelength range is narrowed. Aluminum mirror types use reflections from the aluminum electrodes on the CMOS chip. The reflectivity is inferior to that of the former, but the reflection wavelength range is wider, covering a range of 400 nm to 1550 nm with just three types. For the wavelength band between 1350 and 1400 nm on the -08 type, the reflectance degrades about 5% due to the absorption by the glass substrate. Dielectric mirror types for the 532 nm band are available in - 13 and -16. The -16 is designed to be more light-resistant to short-pulse lasers than the -13.

Spectral response



Electric and optical characteristics

Type no.	Reasout light wavelength (nm)	Light utilization effidiency typ. (%)	Rise time* (ms)	Fall time* (ms)
X15213-01	400 to 700	79 (633 nm)	5 (633 nm)	25 (633 nm)
X15213-02				
X15213-02L	800 ± 50	97 (785 nm)	30 (785 nm)	80 (785 nm)
X15213-02R				
X15213-03				
X15213-03L	1050 ± 50	97 (1064 nm)	25 (1064 nm)	80 (1064 nm)
X15213-03R				
X15213-05	410 ± 10	97 (405 nm)	10 (405 nm)	20 (405 nm)
X15213-07	620 to 1100	82 (1064 nm)	10 (1064 nm)	80 (1064 nm)
X15213-08	1000 to 1550	82 (1064 nm)	30 (1064 nm)	140 (1064 nm)
X15213-13	530 to 635	97 (532 nm)	10 (532 nm)	25 (532 nm)
X15213-16				
X15213-16L	510 ± 50	97 (532 nm)	11 (532 nm)	34 (532 nm)
X15213-16R				

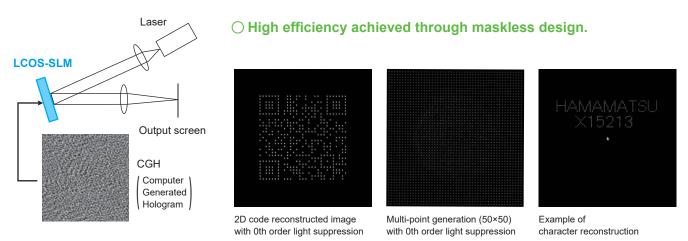
* Time required to change from 10% to 90% for 2π modulation (typical value)

Technologies

Optical beam shaping technology

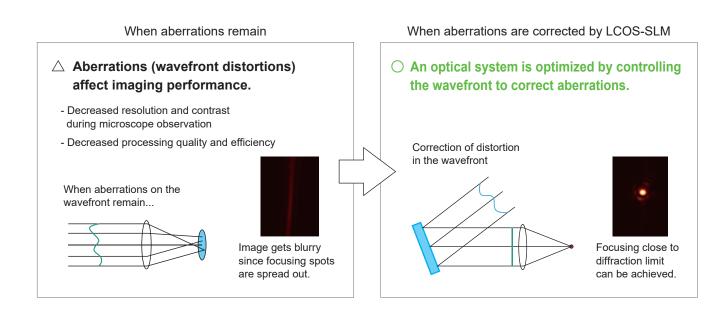
Unlike conventional intensity modulation techniques using masks to block out light to form a desired optical pattern, the LCOS-SLM redistributes the light to generate light patterns efficiently by using phase type holograms.

Optical system



Aberration correction technology

Imaging performance is degraded largely by aberrations that are wavefront distortions on any kind of optical system. In a microscope, the aberrations cause lower resolution and contrast, and in laser processing, they cause lower processing quality and efficiency, for example. An optimum optical system can be achieved by controlling the wavefront to cancel its distortion.



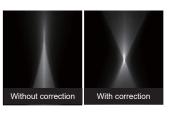
Applications

Multi-point laser material processing

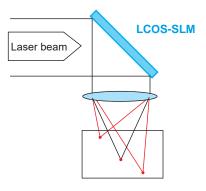
Simultaneous processing with holographic beam-shaping technology

Optical pattern forming technology allows generating multiple laser beams, so high throughput can be achieved by simultaneous multi-point processing. Furthermore, an unprecedented laser processing can be realized by controlling the 3D space including the depth rather than just the 2D plane.

- High speed by multi-point processing
- Depth controllable
- Simultaneous
 aberration correction

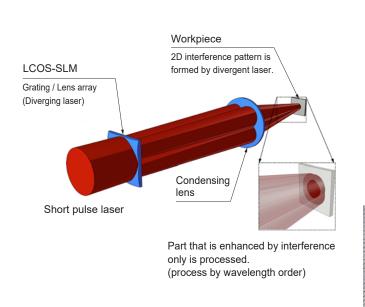


Lateral view of focusing beams



* Joint research with Kyoto University and New Glass Forum in NEDO project

Super-fine multi-point simultaneous laser processing with multiple beam interferometer



Processing examples

ITO layer removal

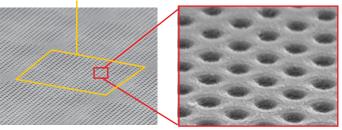
Processing area:

about 500 holes made

Laser: Manufactured by Hamamatsu Ultra-short pulse laser MOIL-ps L11590 SHG 515 nm



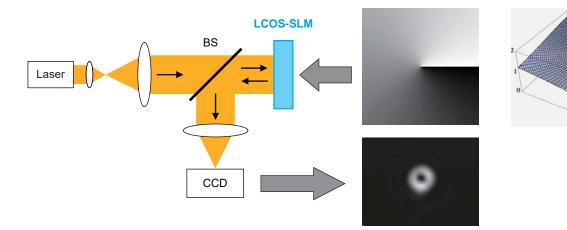
Hole size: 1.5 µm max. in diameter



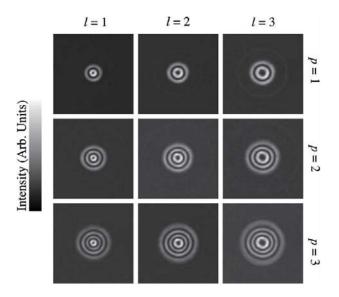
Optical vortex generation

Optical vortex can be generated with a spiral phase distribution modulated by an LCOS-SLM.

Optical system



Result of high order beam generation

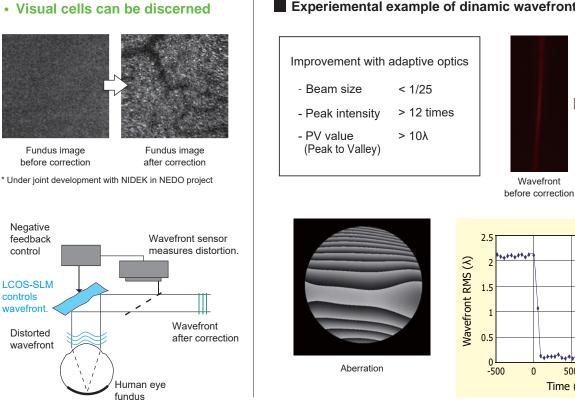


Related thesis

 Structure of optical singularities in coaxial superpositions of Laguerre-Gaussian modes Journal of the Optical Society of America A Vol. 20 No. 2 (2013)133-138

Fundus imaging system using adaptive optics

Dynamically eliminates human eye aberrations for high-resolution ocular fundus imaging.



Experiemental example of dinamic wavefront correction

Without AO RMS=2.09λ With AO RMS=0.06λ 500 1000 1500 Time (ms)

Wavefront

after correction

Optical manipulation (optical tweezers)

Wavefront control for efficient and precise manipulation

Technology for trapping microscopic objects by optical pressure

Biology and science fields need equipment able to handle microscopic objects in large quantities with high precision.

- Multi-point control
- 3D control
- Beam shape control

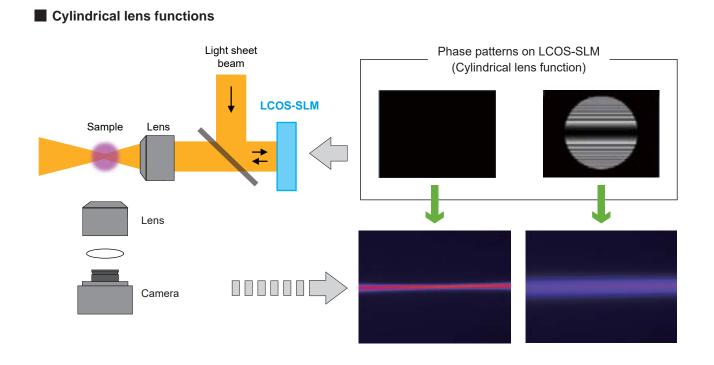
Optical manipulation

Micro-force measurement

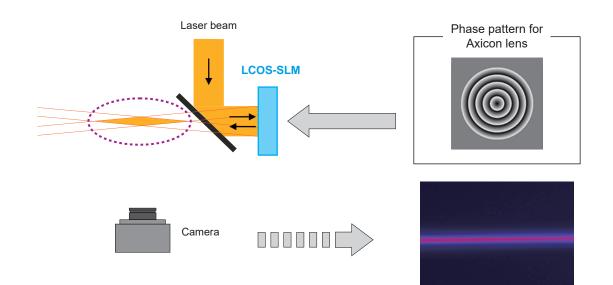
Microscopic object Light input

Beam control: lens function and non-diffractive beam generation

Various beams can be generated and controlled by displaying phase images for lens functions, Bessel beam generation, etc. in the LCOS-SLM, which is expected to be applied to cutting-edge applications such as light sheet microscope, etc.

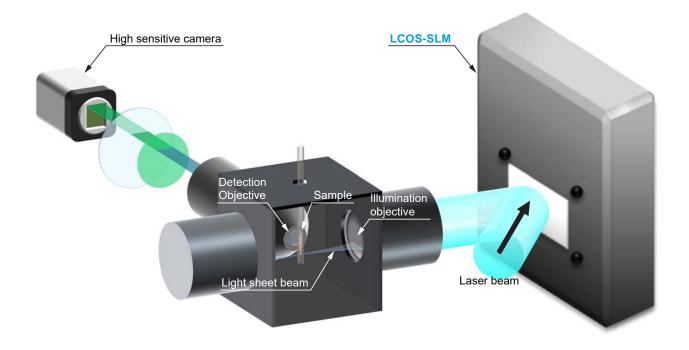


Non-diffractive beam generation



Light sheet microscopy

Light sheet microscopy is one of fluorescent microscopic techniques used for bio-imaging, which can make dramatic reduction of photo toxicity and photo bleaching possible by illuminating a focal plane of a sample only. A lot of beams are being developed as illumination light sources, and a high sensitive camera is used for detection.



LCOS-SLM for material proccessing laser

An optimum LCOS-SLM corresponding to each laser for material processing is indicated in the table below. Unprecedented laser processing can be realized by controlling 3D spaces including depth direction rather than just the processing points on a 2D plane.

Laser type	Yb:YAG, Yb:Fiber	Nd:YAG	Ti:S	Nd:YAG	Nd:YVO4	Yb:YAG, Yb:Fiber
Wavelength (nm)	515	532	800	1064	1064	1030
Optinum LCOS-SLM	X15213-16	X15213-13 X15213-16	X15213-02	X15213-03	X15213-03	X15213-03

Damage type

Damages to LCOS-SLM can be categorized into the 3 types below.

- ① Thermal damage to liquid crystal layer
- 2 Erosive damage to dielectric mirror or aluminum mirror
- ③ Optical damage to liquid crystal material

Thermal damage occurs from excessive input power, and the likely phenomena are described in order as below:

- ① Optical absorption at each constituent material of LCOS-SLM
- ② Temperature increase caused by absorption of light energy
- ③ Degradation of birefringence caused by temperature increase of liquid crystal
- ④ Disappearance of birefringence when liquid crystal temperature reaches phase transition temperature
- ⑤ Irreversible deterioration caused by liquid crystal boiling when temperature increase reaches the limit

The above mentioned thermal damages can be prevented by monitoring the characteristic of birefringence. Erosive damage occurs from excessive peak input power that is beyond a threshold level, and the damage cannot be reversed. LCOS-SLM might be damaged by high-power lasers even though it has high reliability in general. The measurement examples of laser irradiation are indicated in the tables below.

Type-02

			Irradiation intensity		Peak	power	Result				
Туре	Wavelength	Pulse width	Repetition frequency	Beam size [at 1/e ²]	Irradiation time	Average output power	Output power per area	Peak output power	Output power per area	Damage	Characteristic change
Ti:S laser (pulse)	800 nm	50 fs	1 kHz	ф9 mm	3 hours	2.7 W	4.3 W/cm ²	108 GW	170 GW/cm ²	None	Seen
Ti:S laser (pulse)	800 nm	50 fs	1 kHz	¢11 mm	10 hours	2.7 W	2.9 W/cm ²	108 GW	114 GW/cm ²	None	None
Ti:S laser (pulse)	800 nm	30 fs	0.01 kHz	¢18 mm	6 hours	0.05 W	0.02 W/cm ²	333 GW	131 GW/cm ²	None	None

Type-03

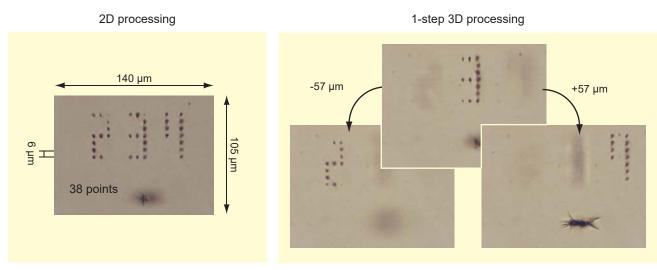
Light source					Irradiation intensity		Peak	power	Result		
Туре	Wavelength	Pulse width	Repetition frequency	Beam size [at 1/e ²]	Irradiation time	Average output power	Output power per area	Peak output power	Output power per area	Damage	Characteristic change
YAG laser (CW)	1064 nm	-	-	¢2.5 mm	1 hour	2.0 W	40.7 W/cm ²	-	-	None	None
YAG laser (CW)	1064 nm	-	-	¢2.5 mm	Several minuits	3.5 W	71.3 W/cm ²	-	-	None	Seen
YAG laser (pulse)	1064 nm	200 ns	80 kHz	φ2.5 mm	1 hour	2.0 W	40.7 W/cm ²	0.25 KW	5.1 KW/cm ²	None	None
YAG laser (pulse)	1064 nm	200 ns	80 kHz	φ2.5 mm	Several minuits	3.5 W	71.3 W/cm ²	0.44 KW	8.9 KW/cm ²	None	Seen
Pulse laser	1030 nm	670 fs	1 kHz	φ4.5 mm	10 hours	0.6 W	3.8 W/cm ²	1.8 GW	11.3 GW/cm ²	None	None
Pulse laser	1030 nm	1.37 ps	30 kHz	φ8.11 mm	8 hours	5.2 W	10.1 W/cm ²	0.25 GW	0.49 GW/cm ²	None	None
Pulse laser	1030 nm	11.4 ns	10 kHz	¢13 mm	8 hours	17.4 W	13.1 W/cm ²	0.31 MW	0.23 MW/cm ²	None	None

Type-13

Light source			0				Irradiation intensity		Peak power		esult
Туре	Wavelength	Pulse width	Repetition frequency	Beam size [at 1/e ²]	Irradiation time	Average output power	Output power per area	Peak output power	Output power per area	Damage	Characteristic change
CW laser	532 nm	-	-	φ8.45 mm	8 hours	10 W	17.8 W/cm ²	-	-	None	None

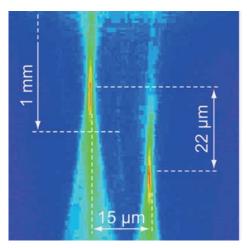
Image gallary

Insite of glass is processed with CGH projection of fs laser



- Objective lens: NA=0.3 (Nikon)
- Irradiation intensity: 250 mW (\$8 mm aperture)
- BK7

Laser beam condensation inside transparent material



Without aberration correction

22 µm

15 µm

With aberration correction

Features

Feature 1

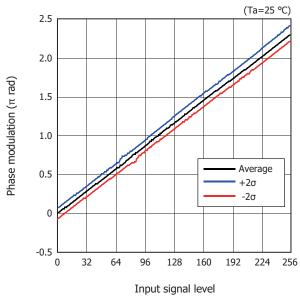
High light utilization efficiency

The X15213 series have high light utilization efficiency, which is defined a ratio of the 0th order diffraction light level to the input light level. The high light utilization efficiency mainly depends on reflectivity, and the amount of diffraction loss caused by the pixel structure. We adopted advanced CMOS technology to make the diffraction loss smaller. As a result, the diffraction loss is less than 5%. The -02/-03/-05/-13/-16 types have a dielectric mirror which has high reflectivity. Therefore, these types have very high light utilization efficiency. The -01/-07/-08 types have relatively low light utilization efficiency compared to the ones with the dielectric mirror but have wide spectral response characteristics.

Feature 2

Pure, linear and precise phase control

The X15213 series can achieve phase modulation of more than 2 π radians over the 400-1550 nm readout wavelength range. The X15213 series comes pre-calibrated from the factory for a specified wavelength range to have more than 2 π radians of phase modulation and its linear characteristics. The figure below shows typical phase modulation characteristics. A phase shift of 2 π radians or more and a linear phase response are achieved. The phase modulation curves for 95% pixels lies within +/- 2 σ .

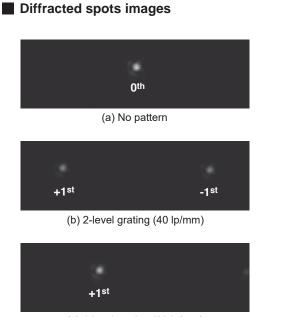


Phase modulation

KACCB0271EA

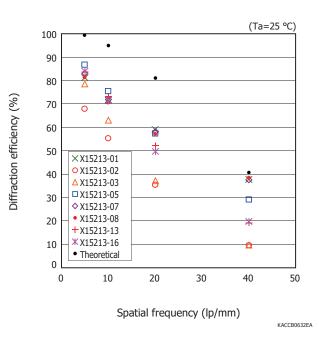
Feature 3 High diffraction efficiency

The X15213 series is a pure phase SLM with high precision phase control; therefore, it has high diffraction efficiency close to the theoretical values. The left figure shows images of diffracted spots, when a multi-level phase grating is formed in the X15213 series. The right figure shows typical diffraction efficiency characteristics. The diffraction efficiency here is the ratio of the 1st order diffraction intensity to the 0th order intensity of light without modulation (no pattern).



(c) 4-level grating (20 lp/mm)

Diffraction efficiency (typical example)

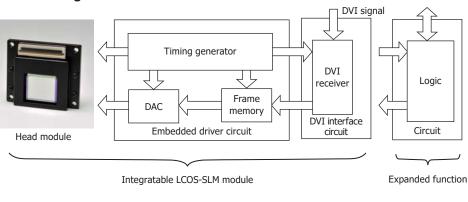


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A compact and low cost driver circuit is connected to a compact head module with a flexible cable. A phase only spatial light modulator can be integrated easily for industrial applications.



Block diagram



FAQ

Q: Do you develop the LCOS-SLM system and the LCOS chip itself in-house?

A: Yes, the whole system including the CMOS backplane and optical thin film is designed and manufactured in-house by HAMAMATSU. This means that the LCOS-SLM is individually optimized to the readout laser and the specific application.

Q: Can you offer custom LCOS-SLM?

A: Yes, as mentioned above, all parts of the LCOS-SLM are designed in-house at the HAMAMATSU factory, meaning that there is a higher degree of flexibility with regard to providing customized LCOS-SLM. Please contact us with your exact requirements, and we'll see what we can do.

Q: Do we need to make baseline measurements for correcting the device characteristic and flatness?

A: No, all LCOS-SLMs are delivered with a linear phase characteristic data, and an individual flatness correction data is provided.

Q: Does your LCOS-SLM show phase fluctuations/flickering?

A: We use carefully designed control electronics to electrically drive the LCOS chip. Consequently, the phase fluctuations and flickering are negligible. For further information, please consult us and we can provide further details.

KACCC1005EA

Q: What is the light utilization efficiency of the LCOS-SLM X15213 series?

A: The total light utilization efficiency is related to the reflectivity and the diffraction loss of the pixel structure. The reflectivity is determined by the "mirror" characteristics of either an aluminum mirror or the highly reflective dielectric mirror with up to 97% reflectivity. Also the pixel fill factor is relevant to minimizing diffraction losses due to the pixel structure (the higher fill factor the better). The diffraction loss is dependent on several factors of the LCOS-SLM design like pixel size, fill factor and LC material.

Q: Is there a special interface needed to control the LCOS-SLM?

A: No, all you need is to use a standard graphics card with a DVI-D output, ideally a card with two DVI-D ports to connect to a monitor and to the LCOS-SLM.

Q: What is the laser damage threshold?

A: It depends if you use the -01/-07/-08 with an aluminum mirror or the -02/-03/-05/-13/-16 with the dielectric mirror. The latter can withstand much higher CW and pulsed laser powers. We tested several lasers, and you can find the results in the LCOS-SLM "Technical Information" (ask us for a copy). If your special laser parameters are not listed, please ask us and we are happy to help ensure you use the LCOS-SLM safely.

Q: What wavelengths does LCOS-SLM operate at?

A: We have a range of LCOS-SLM to cover wavelengths between 400 nm and 1550 nm.

Q: What kind of LCOS-SLM do you manufacture?

A: Our LCOS-SLM uses parallel-aligned, nematic liquid crystals and a CMOS backplane for the addressing. They are reflective devices.

Q: Do you offer demo loans?

A: Yes, we can provide you with a demo system. You can then use the LCOS-SLM in your lab and test its performance directly within your setup. Please contact us to discuss your experiment and arrange the schedule. This demo loan is free of charge for you. We kindly ask you to send it back to our office and summarize your findings on completion of the loan.

Q: Do you got a price list for the SLM?

A: The LCOS-SLM is individually optimized for the user's application and readout laser, so please call or e-mail us to determine which LCOS-SLM will be optimal for your application and we'll provide quotations right away.

Q: What is the delivery time of the LCOS-SLM?

A: The standard delivery time will depend on the manufacturing cycle. The typical lead time is six to eight weeks from receipt of order though sometimes deliveries can be shorter than this, and we do hold some LCOS-SLM in loan stock should something be urgently required.

Q: What is your standard warranty?

A: The standard warranty is 12 months from receipt of product.

Related thesis / Technical materials

Laser processing

- Modified Alvarez lens for high-speed focusing.
 Optics Express 25 (24): 29847-29855 (2017)
- Massively parallel femtosecond laser processing Optics Express 24 (16): 18513-18524 (2016)
- Three-dimensional vector recording in polarization sensitive liquid crystal composites by using axisymmetrically polarized beam.
 Optics Letters 41 (3): 642-645 (2016)
- Abruptly autofocusing beams enable advanced multiscale photo-polymerization.
 Optica 3 (5): 525-530 (2016)
- Laser material processing with tightly focused cylindrical vector beams.
 Applied Physics Letters 108 (22): 221107 (2016)

Adaptive optics

Adaptive optics scanning laser ophthalmoscope using liquid crystal on silicon spatial light modulator : performance study with involuntary eye movement

Jpn. J. Appl. Phys. 56, 09NB02 (2017).

Beam shaping/Pulse shaping

- 9-kW peak power and 150-fs duration blue-violet optical pulses generated by GaInN master oscillator power amplifier. Optics Express 25 (13): 14926-14934 (2017)
- Sub-diffraction-limited fluorescent patterns by tightly focusing polarized femtosecond vortex beams in silver-containing glass.
 Optics Express 25 (9): 10565-10573 (2017)
- Creating a nondiffracting beam with sub-diffraction size by a phase spatial light modulator.
 Optics Express 25 (6): 6274-6282 (2017)
- Vortex-free phase profiles for uniform patterning with computer-generated holography. Optics Express 25 (11): 12640-12652, 2017
- Realization of multiform time derivatives of pulses using a Fourier pulse shaping system.
 Optics Express 25 (4): 4038-4045 (2017)
- Diffractive fan-out elements for wavelength-multiplexing subdiffraction-limit spot generation in three dimensions Applied Optics 55 (23): 6371-6380 (2016)
- Fluid flow vorticity measurement using laser beams with orbital angular momentum. Optics Express 24 (11): 11762-11767 (2016)
- Comparison of beam generation techniques using a phase only spatial light modulator.
 Optics Express 24 (6): 6249-6264 (2016)
- Mode crosstalk matrix measurement of a 1 km elliptical core few-mode optical fiber. Optics Letters 41 (12): 2755-2758 (2016)
- Arbitrary shaping of on-axis amplitude of femtosecond Bessel beams with a single phase-only spatial light modulator. Optics Express 24 (11): 11495-11504 (2016)

- Mitigating self-action processes with chirp or binary phase shaping. Optics Letters 41 (1): 131-134 (2016)
- High-quality generation of a multispot pattern using a spatial light modulator with adaptive Optics Letters 37, 3135 (2012)

Microscopy applications

- Raman imaging through a single multimode fiber.
 Optics Express 25 (12): 13782-13798 (2017)
- Transmission-matrix-based point-spread-function engineering through a complex medium Optica 4 (1): 54-59 (2017)
- Three-dimensional spatiotemporal focusing of holographic patterns. Nature Communications 7: 11928 (2016)
- Colored point spread function engineering for parallel confocal microscopy. Optics Express 24 (24): 27395-27402 (2016)
- Three-dimensional STED microscopy of aberrating tissue using dual adaptive optics. Optics Express 24 (8): 8862-8876 (2016)
- A V0 core neuronal circuit for inspiration.
 Nature Communications 8 (1): 544 (2017)
- An adaptive approach for uniform scanning in multifocal multiphoton microscopy with a spatial light modulator Optics Express 22 (1), 633-645 (2014).

Optical manipulation/others

- Using back focal plane interferometry to probe the influence of Zernike aberrations in optical tweezers.
 Optics Letters 42 (15): 2968-2971 (2017)
- Vector assembly of colloids on monolayer substrates.
 Nature Communications 8: 15778 (2017)
- Cooperative Micromanipulation Using the Independent Actuation of Fifty Microrobots in Parallel.
 Scientific Reports 7 (1): 3278 (2017)
- Single-pixel digital holography with phase-encoded illumination.
 Optics Express 25 (5) 4975-4984 (2017)
- Single-shot incoherent digital holography using a dual-focusing lens with diffraction gratings. Optics Letters 42 (3): 383-386 (2017)
- Shaping of cylindrical and 3D ellipsoidal beams for electron photoinjector laser drivers. Applied Optics 55 (7): 1630-1635 (2016)
- Enhanced terahertz wave emission from air-plasma tailored by abruptly autofocusing laser beams.
 Optica 3 (6): 605-608 (2016)

A list of other related thesis is on the following website. http://www.hamamatsu.com/jp/en/community/lcos/publications/index.html

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